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TECHNOLOGY CENTER 2800

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of

Kiezo Yamada et al.

Serial No. 09/702,831

Filed November 1, 2000

Group Art Unit 2829

Examiner Vinh P. Nguyen

For A SEMICONDUCTOR DEVICE TESTER  
WHICH MEASURES INFORMATION  
RELATED TO A STRUCTURE OF A SAMPLE  
IN DEPTH DIRECTION (as amended)

*14/Reyfo*  
*Recon*  
*+ and B*  
*MacKen*  
*2-4-03*  
*Altair*

Box Non-Fee Amendment  
Assistant Commissioner for Patents  
Washington, D.C. 20231

REQUEST FOR RECONSIDERATION UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action mailed November 19, 2002, please amend the above-identified patent application as follows.

In the Claims:

Please amend the claim 1 as follows. A clean copy of the amended claim is attached.

- 1 Claim 1 (Twice Amended). A semiconductor device tester comprising:
- 2 electron beam irradiation means for irradiating a semiconductor
- 3 device as a sample under test with an electron beam while scanning the
- 4 semiconductor device;
- 5 a current measuring means for measuring current flowing through
- 6 the semiconductor resulting from irradiation by the electron beam; and